



Form PTO 1449  
(Modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

273626US2PCT

SERIAL NO.

10/540,003

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Jerome HAZART

FILING DATE

June 21, 2005

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TN	AA	5,956,145	09/21/99	GREEN, Steven E. et al.			
	AB						
	AC						
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	AM						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
TN	AN	02/27288	04/04/02	WO		NO

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

TN	AO	D. BHATTACHARYYA et al.: "Spectroscopic ellipsometry of multilayer dielectric coatings", Vacuum, Vol. 60, No. 4, pages 419-424, March 2001. XP-002954104				
	AP	Jean GARRIGUES: "La methode des elements finis", 'Onlinel, pages 1-83, January 2002. XP-002254500				
	AQ	Babar K. MINHAS et al.: "Ellipsometric scatterometry for the metrology of sub-0.1- $\mu$ m-linewidth structures", Applied Optics, Vol. 37, No. 22, pages 5112-5115, August 1, 1998. XP-001162836				
	AR	Fred L. TERRY, Jr.: "A modified harmonic oscillator approximation scheme for the dielectric constants of Al <sub>x</sub> Ga <sub>1-x</sub> As", Journal of Applied Physics, Vol. 70, No. 1, pages 409-417, July 1, 1991.				
	AS	R.M.A. AZZAM and N.M. BASHARA: "ELLIPSOMETRY AND POLARIZED LIGHT", Chapter 6, pages 417-486.				
	AT	Max Wolf BORN: "Principles of Optics", 7th, exp. ed. 1999.				
	AU	A. R. FOROUHI: "Optical dispersion relations for amorphous semiconductors and amorphous dielectrics", Physical Review B, Vol. 34, No. 10, pages 7018-7026, November 15, 1986.				
	AV	W. H. PRESS, S. A. TEUKOLSKY, W. T. VETTERLING, B. P. FLANNERY: "Numerical Recipes in C: The Art of Scientific Computing", 2 <sup>nd</sup> Edition, Chapter 3, pages 105-123.				
TN	AW	W. H. PRESS, S. A. TEUKOLSKY, W. T. VETTERLING, B. P. FLANNERY: "Numerical Recipes in C: The Art of Scientific Computing", 2nd Edition, Chapter 10, pages 394-455.				
	AX					
	AY					

☐ Additional References sheet(s) attached

Examiner

Date Considered

2/3/07

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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## LIST OF REFERENCES CITED BY APPLICANT

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
TN	AA	US2006/0077386 A1	04/13/06	Hazart			
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

TN	AW	"High Precision UV-Visible-Near IR Stokes Vector Spectroscopy," Zettle et al.; Thin Solid Films, 234 (1993)
TN	AX	"Ellipsometry on Very Thick Multilayer Structures" Garriga et al., Phys. Stat. Sol. (b) 215, 247 (1999).
TN	AY	"Temperature Dependence of the InP(001) Bulk and Surface Dielectric Function" Zorn et al.; App. Phys. A, 65, 333-339 (1997)
	AZ	

☐ Additional References sheet(s) attached

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